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**Connectors for electronic equipment —
Tests and measurements — Part 6-2 :
Dynamic stress tests — Test 6b : Bump**

ICS 31.220.10

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Foreword

This translation has been made based on the original Japanese Industrial Standard established by the Minister of Economy, Trade and Industry through deliberations at the Japanese Industrial Standards Committee according to the proposal of establishing a Japanese Industrial Standard from Japan Electronics and Information Technology Industries Association (JEITA) with a draft of Industrial Standard based on the provision of Article 12 Clause 1 of the Industrial Standardization Law. This Standard has been made based on IEC 60512-6-2:2002 *Connectors for electronic equipment—Tests and measurements—Part 6-2: Dynamic stress tests—Test 6b: Bump* for the purposes of making it easier to compare this Standard with International Standard; to prepare Japanese Industrial Standard conforming with International Standard; and to propose a draft of an International Standard which is based on Japanese Industrial Standard.

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